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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	600
Number of Logic Elements/Cells	2700
Total RAM Bits	40960
Number of I/O	140
Number of Gates	100000
Voltage - Supply	2.375V ~ 2.625V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	208-BFQFP
Supplier Device Package	208-PQFP (28x28)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc2s100-6pqg208c

Introduction

The Spartan®-II Field-Programmable Gate Array family gives users high performance, abundant logic resources, and a rich feature set, all at an exceptionally low price. The six-member family offers densities ranging from 15,000 to 200,000 system gates, as shown in [Table 1](#). System performance is supported up to 200 MHz. Features include block RAM (to 56K bits), distributed RAM (to 75,264 bits), 16 selectable I/O standards, and four DLLs. Fast, predictable interconnect means that successive design iterations continue to meet timing requirements.

The Spartan-II family is a superior alternative to mask-programmed ASICs. The FPGA avoids the initial cost, lengthy development cycles, and inherent risk of conventional ASICs. Also, FPGA programmability permits design upgrades in the field with no hardware replacement necessary (impossible with ASICs).

Features

- Second generation ASIC replacement technology
 - Densities as high as 5,292 logic cells with up to 200,000 system gates
 - Streamlined features based on Virtex® FPGA architecture
 - Unlimited reprogrammability
 - Very low cost
 - Cost-effective 0.18 micron process
- System level features
 - SelectRAM™ hierarchical memory:
 - 16 bits/LUT distributed RAM
 - Configurable 4K bit block RAM
 - Fast interfaces to external RAM
 - Fully PCI compliant
 - Low-power segmented routing architecture
 - Full readback ability for verification/observability
 - Dedicated carry logic for high-speed arithmetic
 - Efficient multiplier support
 - Cascade chain for wide-input functions
 - Abundant registers/latches with enable, set, reset
 - Four dedicated DLLs for advanced clock control
 - Four primary low-skew global clock distribution nets
 - IEEE 1149.1 compatible boundary scan logic
- Versatile I/O and packaging
 - Pb-free package options
 - Low-cost packages available in all densities
 - Family footprint compatibility in common packages
 - 16 high-performance interface standards
 - Hot swap Compact PCI friendly
 - Zero hold time simplifies system timing
- Core logic powered at 2.5V and I/Os powered at 1.5V, 2.5V, or 3.3V
- Fully supported by powerful Xilinx® ISE® development system
 - Fully automatic mapping, placement, and routing

Table 1: Spartan-II FPGA Family Members

Device	Logic Cells	System Gates (Logic and RAM)	CLB Array (R x C)	Total CLBs	Maximum Available User I/O ⁽¹⁾	Total Distributed RAM Bits	Total Block RAM Bits
XC2S15	432	15,000	8 x 12	96	86	6,144	16K
XC2S30	972	30,000	12 x 18	216	92	13,824	24K
XC2S50	1,728	50,000	16 x 24	384	176	24,576	32K
XC2S100	2,700	100,000	20 x 30	600	176	38,400	40K
XC2S150	3,888	150,000	24 x 36	864	260	55,296	48K
XC2S200	5,292	200,000	28 x 42	1,176	284	75,264	56K

Notes:

1. All user I/O counts do not include the four global clock/user input pins. See details in [Table 2, page 4](#).

Architectural Description

Spartan-II FPGA Array

The Spartan®-II field-programmable gate array, shown in [Figure 2](#), is composed of five major configurable elements:

- IOBs provide the interface between the package pins and the internal logic
- CLBs provide the functional elements for constructing most logic
- Dedicated block RAM memories of 4096 bits each
- Clock DLLs for clock-distribution delay compensation and clock domain control
- Versatile multi-level interconnect structure

As can be seen in [Figure 2](#), the CLBs form the central logic structure with easy access to all support and routing structures. The IOBs are located around all the logic and

memory elements for easy and quick routing of signals on and off the chip.

Values stored in static memory cells control all the configurable logic elements and interconnect resources. These values load into the memory cells on power-up, and can reload if necessary to change the function of the device.

Each of these elements will be discussed in detail in the following sections.

Input/Output Block

The Spartan-II FPGA IOB, as seen in [Figure 2](#), features inputs and outputs that support a wide variety of I/O signaling standards. These high-speed inputs and outputs are capable of supporting various state of the art memory and bus interfaces. [Table 3](#) lists several of the standards which are supported along with the required reference, output and termination voltages needed to meet the standard.

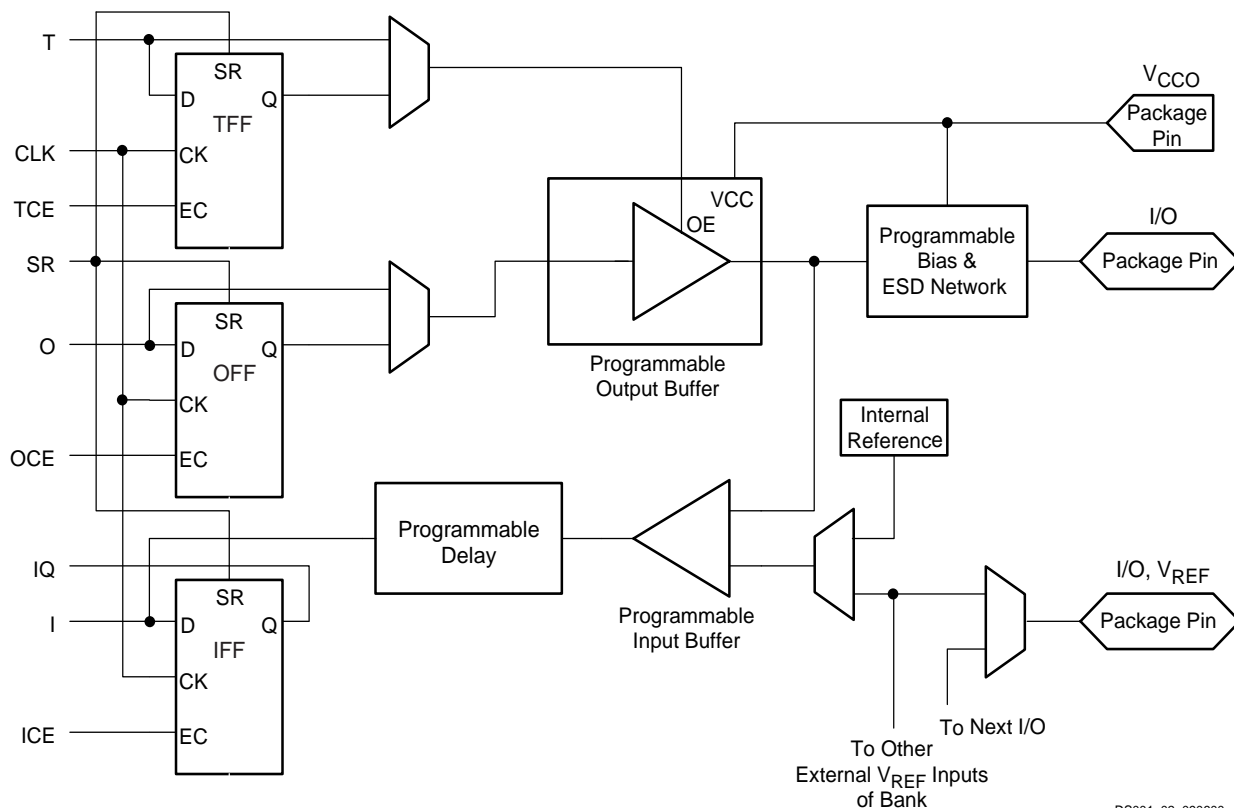


Figure 2: Spartan-II FPGA Input/Output Block (IOB)

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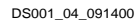


Figure 4: Spartan-II CLB Slice (two identical slices in each CLB)

Storage elements in the Spartan-II FPGA slice can be configured either as edge-triggered D-type flip-flops or as level-sensitive latches. The D inputs can be driven either by function generators within the slice or directly from slice inputs, bypassing the function generators.

opposite state. Alternatively, these signals may be configured to operate asynchronously.

All control signals are independently invertible, and are shared by the two flip-flops within the slice.

The F5 multiplexer in each slice combines the function generator outputs. This combination provides either a function generator that can implement any 5-input function, a 4:1 multiplexer, or selected functions of up to nine inputs.

The figure consists of two parts: a block diagram of the IOB internal structure and a timing diagram.

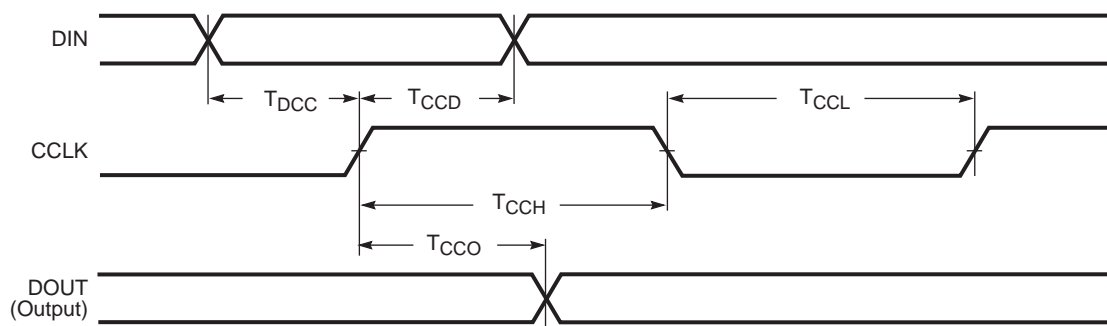
Block Diagram: The IOB is shown as a central block with multiple IOB blocks on the left and right sides. A Bypass Register and an Instruction Register are located at the bottom. A MUX (Multiplexer) is connected to the IOB blocks. The TDI (Test Data In) signal is connected to the IOB blocks. The TDO (Test Data Out) signal is connected to the IOB blocks.

Timing Diagram: The timing diagram shows the internal structure of the IOB blocks. It includes signals for DATA IN, IOB.I, IOB.Q, IOB.T, and IOB.I. The diagram illustrates the internal logic and timing relationships between these signals. The signals are connected to various logic blocks, including D flip-flops, multiplexers, and registers. The timing diagram shows the relationship between the signals and the internal logic blocks, including the D flip-flops, multiplexers, and registers.

Figure 9: Spartan-II Family Boundary Scan Logic

The bit sequence within each IOB is: In, Out, 3-State. The input-only pins contribute only the In bit to the boundary scan I/O data register, while the output-only pins contributes all three bits.

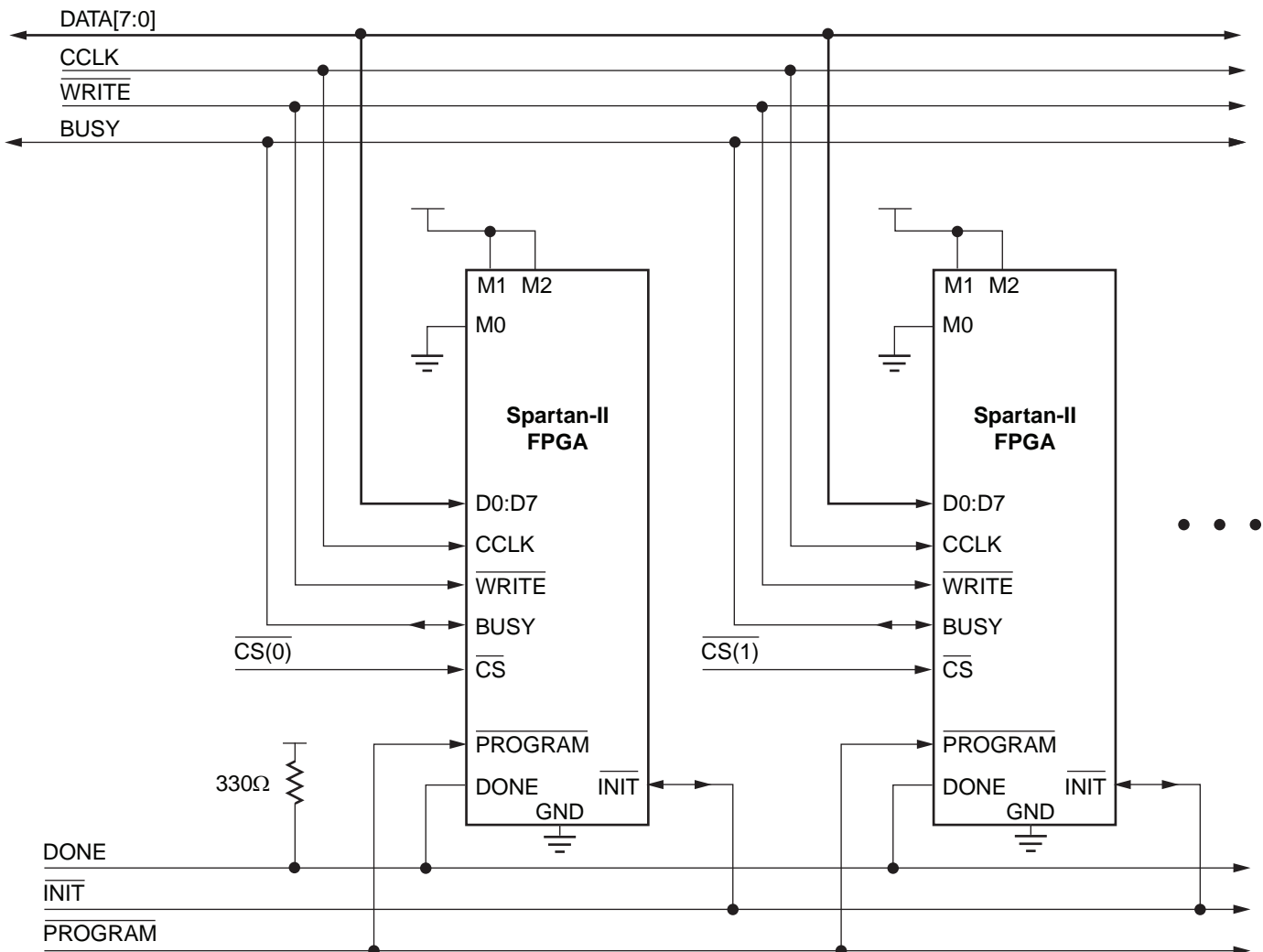
BSDL (Boundary Scan Description Language) files for Spartan-II family devices are available on the Xilinx website, in the [Downloads](#) area.



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Symbol		Description		Units
T _{DCC}	CCLK	DIN setup	5	ns, min
T _{CCD}		DIN hold	0	ns, min
T _{CCO}		DOUT	12	ns, max
T _{CCH}		High time	5	ns, min
T _{CCL}		Low time	5	ns, min
F _{CC}		Maximum frequency	66	MHz, max

Figure 16: Slave Serial Mode Timing



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Figure 18: Slave Parallel Configuration Circuit Diagram

Multiple Spartan-II FPGAs can be configured using the Slave Parallel mode, and be made to start-up simultaneously. To configure multiple devices in this way, wire the individual CCLK, Data, $\overline{\text{WRITE}}$, and BUSY pins of all the devices in parallel. The individual devices are loaded separately by asserting the $\overline{\text{CS}}$ pin of each device in turn and writing the appropriate data. Sync-to-DONE start-up timing is used to ensure that the start-up sequence does not begin until all the FPGAs have been loaded. See "Start-up," page 19.

Write

When using the Slave Parallel Mode, write operations send packets of byte-wide configuration data into the FPGA. Figure 19, page 25 shows a flowchart of the write sequence used to load data into the Spartan-II FPGA. This is an expansion of the "Load Configuration Data Frames" block in Figure 11, page 18. The timing for write operations is shown in Figure 20, page 26.

For the present example, the user holds $\overline{\text{WRITE}}$ and $\overline{\text{CS}}$ Low throughout the sequence of write operations. Note that when $\overline{\text{CS}}$ is asserted on successive CCLKs, $\overline{\text{WRITE}}$ must remain either asserted or de-asserted. Otherwise an abort will be initiated, as in the next section.

1. Drive data onto D0:D7. Note that to avoid contention, the data source should not be enabled while $\overline{\text{CS}}$ is Low and $\overline{\text{WRITE}}$ is High. Similarly, while $\overline{\text{WRITE}}$ is High, no more than one device's $\overline{\text{CS}}$ should be asserted.
2. On the rising edge of CCLK: If BUSY is Low, the data is accepted on this clock. If BUSY is High (from a previous write), the data is not accepted. Acceptance will instead occur on the first clock after BUSY goes Low, and the data must be held until this happens.
3. Repeat steps 1 and 2 until all the data has been sent.
4. De-assert $\overline{\text{CS}}$ and $\overline{\text{WRITE}}$.

BUFGDLL Pin Descriptions

Use the BUFGDLL macro as the simplest way to provide zero propagation delay for a high-fanout on-chip clock from an external input. This macro uses the IBUFG, CLKDLL and BUFG primitives to implement the most basic DLL application as shown in Figure 25.

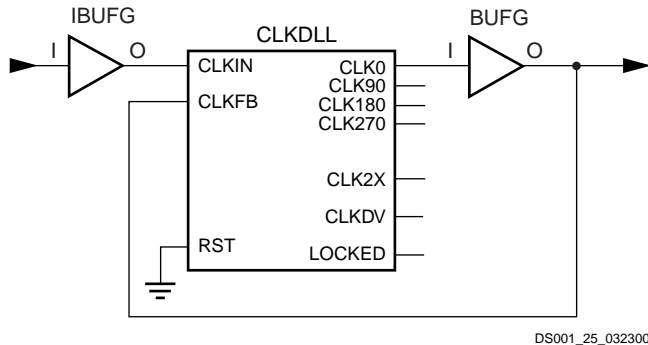


Figure 25: BUFGDLL Block Diagram

This macro does not provide access to the advanced clock domain controls or to the clock multiplication or clock division features of the DLL. This macro also does not provide access to the RST or LOCKED pins of the DLL. For access to these features, a designer must use the DLL primitives described in the following sections.

Source Clock Input — I

The I pin provides the user source clock, the clock signal on which the DLL operates, to the BUFGDLL. For the BUFGDLL macro the source clock frequency must fall in the low frequency range as specified in the data sheet. The BUFGDLL requires an external signal source clock. Therefore, only an external input port can source the signal that drives the BUFGDLL I pin.

Clock Output — O

The clock output pin O represents a delay-compensated version of the source clock (I) signal. This signal, sourced by a global clock buffer BUFG primitive, takes advantage of the dedicated global clock routing resources of the device.

The output clock has a 50/50 duty cycle unless you deactivate the duty cycle correction property.

CLKDLL Primitive Pin Descriptions

The library CLKDLL primitives provide access to the complete set of DLL features needed when implementing more complex applications with the DLL.

Source Clock Input — CLKIN

The CLKIN pin provides the user source clock (the clock signal on which the DLL operates) to the DLL. The CLKIN frequency must fall in the ranges specified in the data sheet. A global clock buffer (BUFG) driven from another CLKDLL

or one of the global clock input buffers (IBUFG) on the same edge of the device (top or bottom) must source this clock signal.

Feedback Clock Input — CLKFB

The DLL requires a reference or feedback signal to provide the delay-compensated output. Connect only the CLK0 or CLK2X DLL outputs to the feedback clock input (CLKFB) pin to provide the necessary feedback to the DLL. Either a global clock buffer (BUFG) or one of the global clock input buffers (IBUFG) on the same edge of the device (top or bottom) must source this clock signal.

If an IBUFG sources the CLKFB pin, the following special rules apply.

1. An external input port must source the signal that drives the IBUFG I pin.
2. The CLK2X output must feed back to the device if both the CLK0 and CLK2X outputs are driving off chip devices.
3. That signal must directly drive only OBUFs and nothing else.

These rules enable the software to determine which DLL clock output sources the CLKFB pin.

Reset Input — RST

When the reset pin RST activates, the LOCKED signal deactivates within four source clock cycles. The RST pin, active High, must either connect to a dynamic signal or be tied to ground. As the DLL delay taps reset to zero, glitches can occur on the DLL clock output pins. Activation of the RST pin can also severely affect the duty cycle of the clock output pins. Furthermore, the DLL output clocks no longer deskew with respect to one another. The DLL must be reset when the input clock frequency changes, if the device is reconfigured in Boundary-Scan mode, if the device undergoes a hot swap, and after the device is configured if the input clock is not stable during the startup sequence.

2x Clock Output — CLK2X

The output pin CLK2X provides a frequency-doubled clock with an automatic 50/50 duty-cycle correction. Until the CLKDLL has achieved lock, the CLK2X output appears as a 1x version of the input clock with a 25/75 duty cycle. This behavior allows the DLL to lock on the correct edge with respect to source clock. This pin is not available on the CLKDLLHF primitive.

Clock Divide Output — CLKDV

The clock divide output pin CLKDV provides a lower frequency version of the source clock. The CLKDV_DIVIDE property controls CLKDV such that the source clock is divided by N where N is either 1.5, 2, 2.5, 3, 4, 5, 8, or 16.

This feature provides automatic duty cycle correction. The CLKDV output pin has a 50/50 duty cycle for all values of the

division factor N except for non-integer division in High Frequency (HF) mode. For division factor 1.5 the duty cycle in the HF mode is 33.3% High and 66.7% Low. For division factor 2.5, the duty cycle in the HF mode is 40.0% High and 60.0% Low.

1x Clock Outputs — CLK[0/90/180/270]

The 1x clock output pin CLK0 represents a delay-compensated version of the source clock (CLKIN) signal. The CLKDLL primitive provides three phase-shifted versions of the CLK0 signal while CLKDLLHF provides only the 180 degree phase-shifted version. The relationship between phase shift and the corresponding period shift appears in [Table 10](#).

The timing diagrams in [Figure 26](#) illustrate the DLL clock output characteristics.

Table 10: Relationship of Phase-Shifted Output Clock to Period Shift

Phase (degrees)	Period Shift (percent)
0	0%
90	25%
180	50%
270	75%

The DLL provides duty cycle correction on all 1x clock outputs such that all 1x clock outputs by default have a 50/50 duty cycle. The DUTY_CYCLE_CORRECTION property (TRUE by default), controls this feature. In order to deactivate the DLL duty cycle correction, attach the DUTY_CYCLE_CORRECTION=FALSE property to the DLL primitive. When duty cycle correction deactivates, the output clock has the same duty cycle as the source clock.

The DLL clock outputs can drive an OBUF, a BUFG, or they can route directly to destination clock pins. The DLL clock outputs can only drive the BUFGs that reside on the same edge (top or bottom).

Locked Output — LOCKED

In order to achieve lock, the DLL may need to sample several thousand clock cycles. After the DLL achieves lock the LOCKED signal activates. The ["DLL Timing Parameters"](#) section of Module 3 provides estimates for locking times.

In order to guarantee that the system clock is established prior to the device "waking up," the DLL can delay the completion of the device configuration process until after the DLL locks. The STARTUP_WAIT property activates this feature.

Until the LOCKED signal activates, the DLL output clocks are not valid and can exhibit glitches, spikes, or other

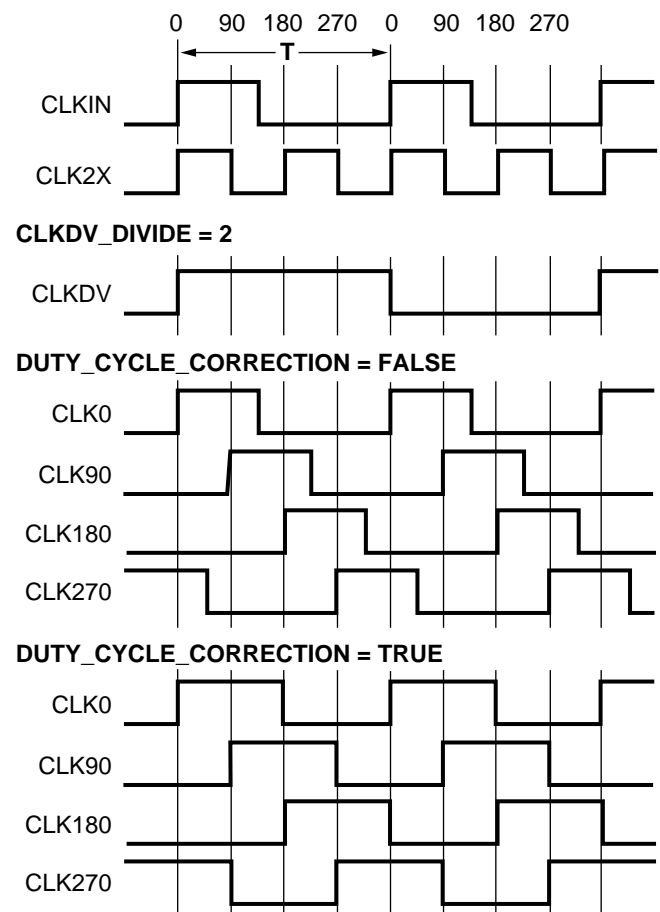
spurious movement. In particular the CLK2X output will appear as a 1x clock with a 25/75 duty cycle.

DLL Properties

Properties provide access to some of the Spartan-II family DLL features, (for example, clock division and duty cycle correction).

Duty Cycle Correction Property

The 1x clock outputs, CLK0, CLK90, CLK180, and CLK270, use the duty-cycle corrected default, such that they exhibit a 50/50 duty cycle. The DUTY_CYCLE_CORRECTION property (by default TRUE) controls this feature. To deactivate the DLL duty-cycle correction for the 1x clock outputs, attach the DUTY_CYCLE_CORRECTION=FALSE property to the DLL primitive.



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Figure 26: DLL Output Characteristics

Clock Divide Property

The CLKDV_DIVIDE property specifies how the signal on the CLKDV pin is frequency divided with respect to the CLK0 pin. The values allowed for this property are 1.5, 2, 2.5, 3, 4, 5, 8, or 16; the default value is 2.

Creating Larger RAM Structures

The block RAM columns have specialized routing to allow cascading blocks together with minimal routing delays. This achieves wider or deeper RAM structures with a smaller timing penalty than when using normal routing channels.

Location Constraints

Block RAM instances can have LOC properties attached to them to constrain the placement. The block RAM placement locations are separate from the CLB location naming convention, allowing the LOC properties to transfer easily from array to array.

The LOC properties use the following form:

LOC = RAMB4_R#C#

RAMB4_R0C0 is the upper left RAMB4 location on the device.

Conflict Resolution

The block RAM memory is a true dual-read/write port RAM that allows simultaneous access of the same memory cell from both ports. When one port writes to a given memory cell, the other port must not address that memory cell (for a write or a read) within the clock-to-clock setup window. The following lists specifics of port and memory cell write conflict resolution.

- If both ports write to the same memory cell simultaneously, violating the clock-to-clock setup requirement, consider the data stored as invalid.
- If one port attempts a read of the same memory cell the other simultaneously writes, violating the clock-to-clock setup requirement, the following occurs.
 - The write succeeds
 - The data out on the writing port accurately reflects the data written.
 - The data out on the reading port is invalid.

Conflicts do not cause any physical damage.

Single Port Timing

Figure 33 shows a timing diagram for a single port of a block RAM memory. The block RAM AC switching characteristics are specified in the data sheet. The block RAM memory is initially disabled.

At the first rising edge of the CLK pin, the ADDR, DI, EN, WE, and RST pins are sampled. The EN pin is High and the WE pin is Low indicating a read operation. The DO bus contains the contents of the memory location, 0x00, as indicated by the ADDR bus.

At the second rising edge of the CLK pin, the ADDR, DI, EN, WR, and RST pins are sampled again. The EN and WE pins are High indicating a write operation. The DO bus mirrors

the DI bus. The DI bus is written to the memory location 0x0F.

At the third rising edge of the CLK pin, the ADDR, DI, EN, WR, and RST pins are sampled again. The EN pin is High and the WE pin is Low indicating a read operation. The DO bus contains the contents of the memory location 0x7E as indicated by the ADDR bus.

At the fourth rising edge of the CLK pin, the ADDR, DI, EN, WR, and RST pins are sampled again. The EN pin is Low indicating that the block RAM memory is now disabled. The DO bus retains the last value.

Dual Port Timing

Figure 34 shows a timing diagram for a true dual-port read/write block RAM memory. The clock on port A has a longer period than the clock on Port B. The timing parameter T_{BCCS} , (clock-to-clock setup) is shown on this diagram. The parameter, T_{BCCS} is violated once in the diagram. All other timing parameters are identical to the single port version shown in Figure 33.

T_{BCCS} is only of importance when the address of both ports are the same and at least one port is performing a write operation. When the clock-to-clock set-up parameter is violated for a WRITE-WRITE condition, the contents of the memory at that location will be invalid. When the clock-to-clock set-up parameter is violated for a WRITE-READ condition, the contents of the memory will be correct, but the read port will have invalid data. At the first rising edge of the CLKA, memory location 0x00 is to be written with the value 0xAAAA and is mirrored on the DOA bus. The last operation of Port B was a read to the same memory location 0x00. The DOB bus of Port B does not change with the new value on Port A, and retains the last read value. A short time later, Port B executes another read to memory location 0x00, and the DOB bus now reflects the new memory value written by Port A.

At the second rising edge of CLKA, memory location 0x7E is written with the value 0x9999 and is mirrored on the DOA bus. Port B then executes a read operation to the same memory location without violating the T_{BCCS} parameter and the DOB reflects the new memory values written by Port A.

Definition of Terms

In this document, some specifications may be designated as Advance or Preliminary. These terms are defined as follows:

Advance: Initial estimates based on simulation and/or extrapolation from other speed grades, devices, or families. Values are subject to change. Use as estimates, not for production.

Preliminary: Based on preliminary characterization. Further changes are not expected.

Unmarked: Specifications not identified as either Advance or Preliminary are to be considered Final.

Except for pin-to-pin input and output parameters, the AC parameter delay specifications included in this document are derived from measuring internal test patterns. All limits are representative of worst-case supply voltage and junction temperature conditions. Typical numbers are based on measurements taken at a nominal V_{CCINT} level of 2.5V and a junction temperature of 25°C. The parameters included are common to popular designs and typical applications. **All specifications are subject to change without notice.**

DC Specifications

Absolute Maximum Ratings⁽¹⁾

Symbol	Description	Min	Max	Units
V_{CCINT}	Supply voltage relative to GND ⁽²⁾	-0.5	3.0	V
V_{CCO}	Supply voltage relative to GND ⁽²⁾	-0.5	4.0	V
V_{REF}	Input reference voltage	-0.5	3.6	V
V_{IN}	Input voltage relative to GND ⁽³⁾			
	5V tolerant I/O ⁽⁴⁾	-0.5	5.5	V
	No 5V tolerance ⁽⁵⁾	-0.5	$V_{CCO} + 0.5$	V
V_{TS}	Voltage applied to 3-state output			
	5V tolerant I/O ⁽⁴⁾	-0.5	5.5	V
	No 5V tolerance ⁽⁵⁾	-0.5	$V_{CCO} + 0.5$	V
T_{STG}	Storage temperature (ambient)	-65	+150	°C
T_J	Junction temperature	-	+125	°C

Notes:

- Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those listed under Operating Conditions is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time may affect device reliability.
- Power supplies may turn on in any order.
- V_{IN} should not exceed V_{CCO} by more than 3.6V over extended periods of time (e.g., longer than a day).
- Spartan®-II device I/Os are 5V Tolerant whenever the LVTTTL, LVCMOS2, or PCI33_5 signal standard has been selected. With 5V Tolerant I/Os selected, the Maximum DC overshoot must be limited to either +5.5V or 10 mA, and undershoot must be limited to either -0.5V or 10 mA, whichever is easier to achieve. The Maximum AC conditions are as follows: The device pins may undershoot to -2.0V or overshoot to +7.0V, provided this over/undershoot lasts no more than 11 ns with a forcing current no greater than 100 mA.
- Without 5V Tolerant I/Os selected, the Maximum DC overshoot must be limited to either $V_{CCO} + 0.5V$ or 10 mA, and undershoot must be limited to -0.5V or 10 mA, whichever is easier to achieve. The Maximum AC conditions are as follows: The device pins may undershoot to -2.0V or overshoot to $V_{CCO} + 2.0V$, provided this over/undershoot lasts no more than 11 ns with a forcing current no greater than 100 mA.
- For soldering guidelines, see the [Packaging Information](#) on the Xilinx® web site.

Power-On Requirements

Spartan-II FPGAs require that a minimum supply current I_{CCPO} be provided to the V_{CCINT} lines for a successful power-on. If more current is available, the FPGA can consume more than I_{CCPO} minimum, though this cannot adversely affect reliability.

A maximum limit for I_{CCPO} is not specified. Therefore the use of foldback/crowbar supplies and fuses deserves special attention. In these cases, limit the I_{CCPO} current to a level below the trip point for over-current protection in order to avoid inadvertently shutting down the supply.

Symbol	Description	Conditions		New Requirements ⁽¹⁾ For Devices with Date Code 0321 or Later		Old Requirements ⁽¹⁾ For Devices with Date Code before 0321		Units
		Junction Temperature ⁽²⁾	Device Temperature Grade	Min	Max	Min	Max	
$I_{CCPO}^{(3)}$	Total V_{CCINT} supply current required during power-on	$-40^{\circ}\text{C} \leq T_J < -20^{\circ}\text{C}$	Industrial	1.50	-	2.00	-	A
		$-20^{\circ}\text{C} \leq T_J < 0^{\circ}\text{C}$	Industrial	1.00	-	2.00	-	A
		$0^{\circ}\text{C} \leq T_J \leq 85^{\circ}\text{C}$	Commercial	0.25	-	0.50	-	A
		$85^{\circ}\text{C} < T_J \leq 100^{\circ}\text{C}$	Industrial	0.50	-	0.50	-	A
$T_{CCPO}^{(4,5)}$	V_{CCINT} ramp time	$-40^{\circ}\text{C} \leq T_J \leq 100^{\circ}\text{C}$	All	-	50	-	50	ms

Notes:

- The date code is printed on the top of the device's package. See the "Device Part Marking" section in Module 1.
- The expected T_J range for the design determines the I_{CCPO} minimum requirement. Use the applicable ranges in the junction temperature column to find the associated current values in the appropriate new or old requirements column according to the date code. Then choose the highest of these current values to serve as the minimum I_{CCPO} requirement that must be met. For example, if the junction temperature for a given design is $-25^{\circ}\text{C} \leq T_J \leq 75^{\circ}\text{C}$, then the new minimum I_{CCPO} requirement is 1.5A. If $5^{\circ}\text{C} \leq T_J \leq 90^{\circ}\text{C}$, then the new minimum I_{CCPO} requirement is 0.5A.
- The I_{CCPO} requirement applies for a brief time (commonly only a few milliseconds) when V_{CCINT} ramps from 0 to 2.5V.
- The ramp time is measured from GND to V_{CCINT} max on a fully loaded board.
- During power-on, the V_{CCINT} ramp must increase steadily in voltage with no dips.
- For more information on designing to meet the power-on specifications, refer to the application note [XAPP450 "Power-On Current Requirements for the Spartan-II and Spartan-II-E Families"](#)

DC Input and Output Levels

Values for V_{IL} and V_{IH} are recommended input voltages. Values for V_{OL} and V_{OH} are guaranteed output voltages over the recommended operating conditions. Only selected standards are tested. These are chosen to ensure that all

standards meet their specifications. The selected standards are tested at minimum V_{CCO} with the respective I_{OL} and I_{OH} currents shown. Other standards are sample tested.

Input/Output Standard	V_{IL}		V_{IH}		V_{OL}	V_{OH}	I_{OL}	I_{OH}
	V, Min	V, Max	V, Min	V, Max	V, Max	V, Min	mA	mA
LVTTL ⁽¹⁾	-0.5	0.8	2.0	5.5	0.4	2.4	24	-24
LVC MOS2	-0.5	0.7	1.7	5.5	0.4	1.9	12	-12
PCI, 3.3V	-0.5	44% V_{CCINT}	60% V_{CCINT}	$V_{CCO} + 0.5$	10% V_{CCO}	90% V_{CCO}	Note (2)	Note (2)
PCI, 5.0V	-0.5	0.8	2.0	5.5	0.55	2.4	Note (2)	Note (2)
GTL	-0.5	$V_{REF} - 0.05$	$V_{REF} + 0.05$	3.6	0.4	N/A	40	N/A
GTL+	-0.5	$V_{REF} - 0.1$	$V_{REF} + 0.1$	3.6	0.6	N/A	36	N/A
HSTL I	-0.5	$V_{REF} - 0.1$	$V_{REF} + 0.1$	3.6	0.4	$V_{CCO} - 0.4$	8	-8
HSTL III	-0.5	$V_{REF} - 0.1$	$V_{REF} + 0.1$	3.6	0.4	$V_{CCO} - 0.4$	24	-8
HSTL IV	-0.5	$V_{REF} - 0.1$	$V_{REF} + 0.1$	3.6	0.4	$V_{CCO} - 0.4$	48	-8
SSTL3 I	-0.5	$V_{REF} - 0.2$	$V_{REF} + 0.2$	3.6	$V_{REF} - 0.6$	$V_{REF} + 0.6$	8	-8
SSTL3 II	-0.5	$V_{REF} - 0.2$	$V_{REF} + 0.2$	3.6	$V_{REF} - 0.8$	$V_{REF} + 0.8$	16	-16
SSTL2 I	-0.5	$V_{REF} - 0.2$	$V_{REF} + 0.2$	3.6	$V_{REF} - 0.6$	$V_{REF} + 0.6$	7.6	-7.6
SSTL2 II	-0.5	$V_{REF} - 0.2$	$V_{REF} + 0.2$	3.6	$V_{REF} - 0.8$	$V_{REF} + 0.8$	15.2	-15.2

CLB Switching Characteristics

Delays originating at F/G inputs vary slightly according to the input used. The values listed below are worst-case. Precise values are provided by the timing analyzer.

Symbol	Description	Speed Grade				Units
		-6		-5		
		Min	Max	Min	Max	
Combinatorial Delays						
T _{ILO}	4-input function: F/G inputs to X/Y outputs	-	0.6	-	0.7	ns
T _{IF5}	5-input function: F/G inputs to F5 output	-	0.7	-	0.9	ns
T _{IF5X}	5-input function: F/G inputs to X output	-	0.9	-	1.1	ns
T _{IF6Y}	6-input function: F/G inputs to Y output via F6 MUX	-	1.0	-	1.1	ns
T _{F5INY}	6-input function: F5IN input to Y output	-	0.4	-	0.4	ns
T _{IFNCTL}	Incremental delay routing through transparent latch to XQ/YQ outputs	-	0.7	-	0.9	ns
T _{BYYB}	BY input to YB output	-	0.6	-	0.7	ns
Sequential Delays						
T _{CKO}	FF clock CLK to XQ/YQ outputs	-	1.1	-	1.3	ns
T _{CKLO}	Latch clock CLK to XQ/YQ outputs	-	1.2	-	1.5	ns
Setup/Hold Times with Respect to Clock CLK ⁽¹⁾						
T _{ICK} / T _{CKI}	4-input function: F/G inputs	1.3 / 0	-	1.4 / 0	-	ns
T _{IF5CK} / T _{CKIF5}	5-input function: F/G inputs	1.6 / 0	-	1.8 / 0	-	ns
T _{F5INCK} / T _{CKF5IN}	6-input function: F5IN input	1.0 / 0	-	1.1 / 0	-	ns
T _{IF6CK} / T _{CKIF6}	6-input function: F/G inputs via F6 MUX	1.6 / 0	-	1.8 / 0	-	ns
T _{DICK} / T _{CKDI}	BX/BY inputs	0.8 / 0	-	0.8 / 0	-	ns
T _{CECK} / T _{CKCE}	CE input	0.9 / 0	-	0.9 / 0	-	ns
T _{RCK} / T _{CKR}	SR/BY inputs (synchronous)	0.8 / 0	-	0.8 / 0	-	ns
Clock CLK						
T _{CH}	Minimum pulse width, High	-	1.9	-	1.9	ns
T _{CL}	Minimum pulse width, Low	-	1.9	-	1.9	ns
Set/Reset						
T _{RPW}	Minimum pulse width, SR/BY inputs	3.1	-	3.1	-	ns
T _{RQ}	Delay from SR/BY inputs to XQ/YQ outputs (asynchronous)	-	1.1	-	1.3	ns
T _{IOGSRQ}	Delay from GSR to XQ/YQ outputs	-	9.9	-	11.7	ns
F _{TOG}	Toggle frequency (for export control)	-	263	-	263	MHz

Notes:

1. A zero hold time listing indicates no hold time or a negative hold time.

Revision History

Date	Version No.	Description
09/18/00	2.0	Sectioned the Spartan-II Family data sheet into four modules. Updated timing to reflect the latest speed files. Added current supply numbers and XC2S200 -5 timing numbers. Approved -5 timing numbers as preliminary information with exceptions as noted.
11/02/00	2.1	Removed Power Down feature.
01/19/01	2.2	DC and timing numbers updated to Preliminary for the XC2S50 and XC2S100. Industrial power-on current specifications and -6 DLL timing numbers added. Power-on specification clarified.
03/09/01	2.3	Added note on power sequencing. Clarified power-on current requirement.
08/28/01	2.4	Added -6 preliminary timing. Added typical and industrial standby current numbers. Specified min. power-on current by junction temperature instead of by device type (Commercial vs. Industrial). Eliminated minimum V_{CCINT} ramp time requirement. Removed footnote limiting DLL operation to the Commercial temperature range.
07/26/02	2.5	Clarified that I/O leakage current is specified over the Recommended Operating Conditions for V_{CCINT} and V_{CCO} .
08/26/02	2.6	Added references for XAPP450 to Power-On Current Specification.
09/03/03	2.7	Added relaxed minimum power-on current (I_{CCPO}) requirements to page 53 . On page 64 , moved T_{RPW} values from maximum to minimum column.
06/13/08	2.8	Updated I/O measurement thresholds. Updated description and links. Updated all modules for continuous page, figure, and table numbering. Synchronized all modules to v2.8.

Pinout Tables

The following device-specific pinout tables include all packages available for each Spartan®-II device. They follow the pad locations around the die, and include Boundary Scan register locations.

XC2S15 Device Pinouts

XC2S15 Pad Name		VQ100	TQ144	CS144	Bndry Scan
Function	Bank				
GND	-	P1	P143	A1	-
TMS	-	P2	P142	B1	-
I/O	7	P3	P141	C2	77
I/O	7	-	P140	C1	80
I/O, V _{REF}	7	P4	P139	D4	83
I/O	7	P5	P137	D2	86
I/O	7	P6	P136	D1	89
GND	-	-	P135	E4	-
I/O	7	P7	P134	E3	92
I/O	7	-	P133	E2	95
I/O, V _{REF}	7	P8	P132	E1	98
I/O	7	P9	P131	F4	101
I/O	7	-	P130	F3	104
I/O, IRDY ⁽¹⁾	7	P10	P129	F2	107
GND	-	P11	P128	F1	-
V _{CCO}	7	P12	P127	G2	-
V _{CCO}	6	P12	P127	G2	-
I/O, TRDY ⁽¹⁾	6	P13	P126	G1	110
V _{CCINT}	-	P14	P125	G3	-
I/O	6	-	P124	G4	113
I/O	6	P15	P123	H1	116
I/O, V _{REF}	6	P16	P122	H2	119
I/O	6	-	P121	H3	122
I/O	6	P17	P120	H4	125
GND	-	-	P119	J1	-
I/O	6	P18	P118	J2	128
I/O	6	P19	P117	J3	131
I/O, V _{REF}	6	P20	P115	K1	134
I/O	6	-	P114	K2	137
I/O	6	P21	P113	K3	140
I/O	6	P22	P112	L1	143
M1	-	P23	P111	L2	146
GND	-	P24	P110	L3	-
M0	-	P25	P109	M1	147
V _{CCO}	6	P26	P108	M2	-
V _{CCO}	5	P26	P107	N1	-

XC2S15 Device Pinouts (Continued)

XC2S15 Pad Name		VQ100	TQ144	CS144	Bndry Scan
Function	Bank				
M2	-	P27	P106	N2	148
I/O	5	-	P103	K4	155
I/O, V _{REF}	5	P30	P102	L4	158
I/O	5	P31	P100	N4	161
I/O	5	P32	P99	K5	164
GND	-	-	P98	L5	-
V _{CCINT}	-	P33	P97	M5	-
I/O	5	-	P96	N5	167
I/O	5	-	P95	K6	170
I/O, V _{REF}	5	P34	P94	L6	173
I/O	5	-	P93	M6	176
V _{CCINT}	-	P35	P92	N6	-
I, GCK1	5	P36	P91	M7	185
V _{CCO}	5	P37	P90	N7	-
V _{CCO}	4	P37	P90	N7	-
GND	-	P38	P89	L7	-
I, GCK0	4	P39	P88	K7	186
I/O	4	P40	P87	N8	190
I/O	4	-	P86	M8	193
I/O, V _{REF}	4	P41	P85	L8	196
I/O	4	-	P84	K8	199
I/O	4	-	P83	N9	202
V _{CCINT}	-	P42	P82	M9	-
GND	-	-	P81	L9	-
I/O	4	P43	P80	K9	205
I/O	4	P44	P79	N10	208
I/O, V _{REF}	4	P45	P77	L10	211
I/O	4	-	P76	N11	214
I/O	4	P46	P75	M11	217
I/O	4	P47	P74	L11	220
GND	-	P48	P73	N12	-
DONE	3	P49	P72	M12	223
V _{CCO}	4	P50	P71	N13	-
V _{CCO}	3	P50	P70	M13	-
PROGRAM	-	P51	P69	L12	226
I/O (INIT)	3	P52	P68	L13	227
I/O (D7)	3	P53	P67	K10	230
I/O	3	-	P66	K11	233
I/O, V _{REF}	3	P54	P65	K12	236
I/O	3	P55	P63	J10	239
I/O (D6)	3	P56	P62	J11	242

XC2S30 Device Pinouts (Continued)

XC2S30 Pad Name		VQ100	TQ144	CS144	PQ208	Bndry Scan
Function	Bank					
I/O	4	-	-	-	P87	295
I/O	4	-	-	-	P88	298
I/O	4	-	P84	K8	P89	301
I/O	4	-	P83	N9	P90	304
V _{CCINT}	-	P42	P82	M9	P91	-
V _{CCO}	4	-	-	-	P92	-
GND	-	-	P81	L9	P93	-
I/O	4	P43	P80	K9	P94	307
I/O	4	P44	P79	N10	P95	310
I/O	4	-	P78	M10	P96	313
I/O, V _{REF}	4	P45	P77	L10	P98	316
I/O	4	-	-	-	P99	319
I/O	4	-	P76	N11	P100	322
I/O	4	P46	P75	M11	P101	325
I/O	4	P47	P74	L11	P102	328
GND	-	P48	P73	N12	P103	-
DONE	3	P49	P72	M12	P104	331
V _{CCO}	4	P50	P71	N13	P105	-
V _{CCO}	3	P50	P70	M13	P105	-
PROGRAM	-	P51	P69	L12	P106	334
I/O (INIT)	3	P52	P68	L13	P107	335
I/O (D7)	3	P53	P67	K10	P108	338
I/O	3	-	P66	K11	P109	341
I/O	3	-	-	-	P110	344
I/O, V _{REF}	3	P54	P65	K12	P111	347
I/O	3	-	P64	K13	P113	350
I/O	3	P55	P63	J10	P114	353
I/O (D6)	3	P56	P62	J11	P115	356
GND	-	-	P61	J12	P116	-
V _{CCO}	3	-	-	-	P117	-
I/O (D5)	3	P57	P60	J13	P119	359
I/O	3	P58	P59	H10	P120	362
I/O	3	-	-	-	P121	365
I/O	3	-	-	-	P122	368
I/O	3	-	-	-	P123	371
GND	-	-	-	-	P124	-
I/O, V _{REF}	3	P59	P58	H11	P125	374
I/O (D4)	3	P60	P57	H12	P126	377
I/O	3	-	P56	H13	P127	380
V _{CCINT}	-	P61	P55	G12	P128	-
I/O, TRDY ⁽¹⁾	3	P62	P54	G13	P129	386

XC2S30 Device Pinouts (Continued)

XC2S30 Pad Name		VQ100	TQ144	CS144	PQ208	Bndry Scan
Function	Bank					
V _{CCO}	3	P63	P53	G11	P130	-
V _{CCO}	2	P63	P53	G11	P130	-
GND	-	P64	P52	G10	P131	-
I/O, IRDY ⁽¹⁾	2	P65	P51	F13	P132	389
I/O	2	-	-	-	P133	392
I/O	2	-	P50	F12	P134	395
I/O (D3)	2	P66	P49	F11	P135	398
I/O, V _{REF}	2	P67	P48	F10	P136	401
GND	-	-	-	-	P137	-
I/O	2	-	-	-	P138	404
I/O	2	-	-	-	P139	407
I/O	2	-	-	-	P140	410
I/O	2	P68	P47	E13	P141	413
I/O (D2)	2	P69	P46	E12	P142	416
V _{CCO}	2	-	-	-	P144	-
GND	-	-	P45	E11	P145	-
I/O (D1)	2	P70	P44	E10	P146	419
I/O	2	P71	P43	D13	P147	422
I/O	2	-	P42	D12	P148	425
I/O, V _{REF}	2	P72	P41	D11	P150	428
I/O	2	-	-	-	P151	431
I/O	2	-	P40	C13	P152	434
I/O (DIN, D0)	2	P73	P39	C12	P153	437
I/O (DOUT, BUSY)	2	P74	P38	C11	P154	440
CCLK	2	P75	P37	B13	P155	443
V _{CCO}	2	P76	P36	B12	P156	-
V _{CCO}	1	P76	P35	A13	P156	-
TDO	2	P77	P34	A12	P157	-
GND	-	P78	P33	B11	P158	-
TDI	-	P79	P32	A11	P159	-
I/O (CS)	1	P80	P31	D10	P160	0
I/O (WRITE)	1	P81	P30	C10	P161	3
I/O	1	-	P29	B10	P162	6
I/O	1	-	-	-	P163	9
I/O, V _{REF}	1	P82	P28	A10	P164	12
I/O	1	-	-	-	P166	15
I/O	1	P83	P27	D9	P167	18
I/O	1	P84	P26	C9	P168	21
GND	-	-	P25	B9	P169	-
V _{CCO}	1	-	-	-	P170	-

XC2S50 Device Pinouts (Continued)

XC2S50 Pad Name		TQ144	PQ208	FG256	Bndry Scan
Function	Bank				
I/O	0	-	-	D8	83
I/O	0	-	P188	A6	86
I/O, V _{REF}	0	P12	P189	B7	89
GND	-	-	P190	GND*	-
I/O	0	-	P191	C8	92
I/O	0	-	P192	D7	95
I/O	0	-	P193	E7	98
I/O	0	P11	P194	C7	104
I/O	0	P10	P195	B6	107
V _{CCINT}	-	P9	P196	V _{CCINT} *	-
V _{CCO}	0	-	P197	V _{CCO} Bank 0*	-
GND	-	P8	P198	GND*	-
I/O	0	P7	P199	A5	110
I/O	0	P6	P200	C6	113
I/O	0	-	P201	B5	116
I/O	0	-	-	D6	119
I/O	0	-	P202	A4	122
I/O, V _{REF}	0	P5	P203	B4	125
GND	-	-	-	GND*	-
I/O	0	-	P204	E6	128
I/O	0	-	-	D5	131
I/O	0	P4	P205	A3	134
I/O	0	-	-	C5	137
I/O	0	P3	P206	B3	140
TCK	-	P2	P207	C4	-
V _{CCO}	0	P1	P208	V _{CCO} Bank 0*	-
V _{CCO}	7	P144	P208	V _{CCO} Bank 7*	-

04/18/01

Notes:

1. IRDY and TRDY can only be accessed when using Xilinx PCI cores.
2. Pads labelled GND*, V_{CCINT}*, V_{CCO} Bank 0*, V_{CCO} Bank 1*, V_{CCO} Bank 2*, V_{CCO} Bank 3*, V_{CCO} Bank 4*, V_{CCO} Bank 5*, V_{CCO} Bank 6*, V_{CCO} Bank 7* are internally bonded to independent ground or power planes within the package.
3. See "VCCO Banks" for details on V_{CCO} banking.

Additional XC2S50 Package Pins

TQ144

Not Connected Pins					
P104	P105	-	-	-	-

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Additional XC2S100 Package Pins

TQ144

Not Connected Pins					
P104	P105	-	-	-	-

11/02/00

PQ208

Not Connected Pins					
P55	P56	-	-	-	-

11/02/00

FG256

V _{CCINT} Pins					
C3	C14	D4	D13	E5	E12
M5	M12	N4	N13	P3	P14
V _{CCO} Bank 0 Pins					
E8	F8	-	-	-	-
V _{CCO} Bank 1 Pins					
E9	F9	-	-	-	-
V _{CCO} Bank 2 Pins					
H11	H12	-	-	-	-
V _{CCO} Bank 3 Pins					
J11	J12	-	-	-	-
V _{CCO} Bank 4 Pins					
L9	M9	-	-	-	-
V _{CCO} Bank 5 Pins					
L8	M8	-	-	-	-
V _{CCO} Bank 6 Pins					
J5	J6	-	-	-	-
V _{CCO} Bank 7 Pins					
H5	H6	-	-	-	-
GND Pins					
A1	A16	B2	B15	F6	F7
F10	F11	G6	G7	G8	G9
G10	G11	H7	H8	H9	H10
J7	J8	J9	J10	K6	K7
K8	K9	K10	K11	L6	L7
L10	L11	R2	R15	T1	T16
Not Connected Pins					
P4	R4	-	-	-	-

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FG456

V _{CCINT} Pins					
E5	E18	F6	F17	G7	G8
G9	G14	G15	G16	H7	H16
J7	J16	P7	P16	R7	R16
T7	T8	T9	T14	T15	T16
U6	U17	V5	V18	-	-
V _{CCO} Bank 0 Pins					

Additional XC2S100 Package Pins (Continued)

F10	F7	F8	F9	G10	G11
V _{CCO} Bank 1 Pins					
F13	F14	F15	F16	G12	G13
V _{CCO} Bank 2 Pins					
G17	H17	J17	K16	K17	L16
V _{CCO} Bank 3 Pins					
M16	N16	N17	P17	R17	T17
V _{CCO} Bank 4 Pins					
T12	T13	U13	U14	U15	U16
V _{CCO} Bank 5 Pins					
T10	T11	U10	U7	U8	U9
V _{CCO} Bank 6 Pins					
M7	N6	N7	P6	R6	T6
V _{CCO} Bank 7 Pins					
G6	H6	J6	K6	K7	L7
GND Pins					
A1	A22	B2	B21	C3	C20
J9	J10	J11	J12	J13	J14
K9	K10	K11	K12	K13	K14
L9	L10	L11	L12	L13	L14
M9	M10	M11	M12	M13	M14
N9	N10	N11	N12	N13	N14
P9	P10	P11	P12	P13	P14
Y3	Y20	AA2	AA21	AB1	AB22
Not Connected Pins					
A2	A4	A5	A6	A12	A13
A14	A15	A17	B3	B6	B8
B11	B14	B16	B19	C1	C2
C8	C9	C12	C18	C22	D1
D4	D5	D10	D18	D19	D21
E4	E11	E13	E15	E16	E17
E19	E22	F4	F11	F22	G2
G3	G4	G19	G22	H1	H21
J1	J3	J4	J19	J20	K2
K18	K19	L2	L5	L18	L19
M2	M6	M17	M18	M21	N1
N5	N19	P1	P5	P19	P22
R1	R3	R20	R22	T5	T19
U3	U11	U18	V1	V2	V10
V12	V17	V3	V4	V6	V8
V20	V21	V22	W4	W5	W9
W13	W14	W15	W16	W19	Y5
Y14	Y18	Y22	AA1	AA3	AA6
AA9	AA10	AA11	AA16	AA17	AA18
AA22	AB3	AB4	AB7	AB8	AB12
AB14	AB21	-	-	-	-

11/02/00

XC2S150 Device Pinouts (Continued)

XC2S150 Pad Name		PQ208	FG256	FG456	Bndry Scan
Function	Bank				
I/O	4	P90	R11	AA15	595
V _{CCINT}	-	P91	V _{CCINT} *	V _{CCINT} *	-
V _{CCO}	4	P92	V _{CCO} Bank 4*	V _{CCO} Bank 4*	-
GND	-	P93	GND*	GND*	-
I/O	4	P94	M11	Y15	598
I/O, V _{REF}	4	P95	T11	AB16	601
I/O	4	-	-	AB17	604
I/O	4	P96	N11	V15	607
I/O	4	-	R12	Y16	610
I/O	4	-	-	AA17	613
I/O	4	-	-	W16	616
I/O	4	P97	P11	AB18	619
I/O, V _{REF}	4	P98	T12	AB19	622
V _{CCO}	4	-	V _{CCO} Bank 4*	V _{CCO} Bank 4*	-
GND	-	-	GND*	GND*	-
I/O	4	P99	T13	Y17	625
I/O	4	-	N12	V16	628
I/O	4	-	-	AA18	631
I/O	4	-	-	W17	634
I/O	4	P100	R13	AB20	637
GND	-	-	GND*	GND*	-
I/O	4	-	P12	AA19	640
I/O	4	-	-	V17	643
I/O	4	-	-	Y18	646
I/O	4	P101	P13	AA20	649
I/O	4	P102	T14	W18	652
GND	-	P103	GND*	GND*	-
DONE	3	P104	R14	Y19	655
V _{CCO}	4	P105	V _{CCO} Bank 4*	V _{CCO} Bank 4*	-
V _{CCO}	3	P105	V _{CCO} Bank 3*	V _{CCO} Bank 3*	-
PROGRAM	-	P106	P15	W20	658
I/O (INIT)	3	P107	N15	V19	659
I/O (D7)	3	P108	N14	Y21	662
I/O	3	-	-	V20	665
I/O	3	-	-	AA22	668
I/O	3	-	T15	W21	671
GND	-	-	GND*	GND*	-
I/O	3	P109	M13	U20	674

XC2S150 Device Pinouts (Continued)

XC2S150 Pad Name		PQ208	FG256	FG456	Bndry Scan
Function	Bank				
I/O	3	-	-	U19	677
I/O	3	-	-	V21	680
I/O	3	-	R16	T18	683
I/O	3	P110	M14	W22	686
GND	-	-	GND*	GND*	-
V _{CCO}	3	-	V _{CCO} Bank 3*	V _{CCO} Bank 3*	-
I/O, V _{REF}	3	P111	L14	U21	689
I/O	3	P112	M15	T20	692
I/O	3	-	-	T19	695
I/O	3	-	-	V22	698
I/O	3	-	L12	T21	701
I/O	3	P113	P16	R18	704
I/O	3	-	-	U22	707
I/O, V _{REF}	3	P114	L13	R19	710
I/O (D6)	3	P115	N16	T22	713
GND	-	P116	GND*	GND*	-
V _{CCO}	3	P117	V _{CCO} Bank 3*	V _{CCO} Bank 3*	-
V _{CCINT}	-	P118	V _{CCINT} *	V _{CCINT} *	-
I/O (D5)	3	P119	M16	R21	716
I/O	3	P120	K14	P18	719
I/O	3	-	-	P19	725
I/O	3	-	L16	P20	728
I/O	3	P121	K13	P21	731
I/O	3	-	-	N19	734
I/O	3	P122	L15	N18	740
I/O	3	P123	K12	N20	743
GND	-	P124	GND*	GND*	-
V _{CCO}	3	-	V _{CCO} Bank 3*	V _{CCO} Bank 3*	-
I/O, V _{REF}	3	P125	K16	N21	746
I/O (D4)	3	P126	J16	N22	749
I/O	3	-	J14	M19	752
I/O	3	P127	K15	M20	755
I/O	3	-	-	M18	758
V _{CCINT}	-	P128	V _{CCINT} *	V _{CCINT} *	-
I/O, TRDY ⁽¹⁾	3	P129	J15	M22	764
V _{CCO}	3	P130	V _{CCO} Bank 3*	V _{CCO} Bank 3*	-
V _{CCO}	2	P130	V _{CCO} Bank 2*	V _{CCO} Bank 2*	-
GND	-	P131	GND*	GND*	-

XC2S150 Device Pinouts (Continued)

XC2S150 Pad Name		PQ208	FG256	FG456	Bndry Scan
Function	Bank				
I/O, IRDY ⁽¹⁾	2	P132	H16	L20	767
I/O	2	P133	H14	L17	770
I/O	2	-	-	L18	773
I/O	2	P134	H15	L21	776
I/O	2	-	J13	L22	779
I/O (D3)	2	P135	G16	K20	782
I/O, V _{REF}	2	P136	H13	K21	785
V _{CCO}	2	-	V _{CCO} Bank 2*	V _{CCO} Bank 2*	-
GND	-	P137	GND*	GND*	-
I/O	2	P138	G14	K22	788
I/O	2	P139	G15	J21	791
I/O	2	-	-	J20	797
I/O	2	P140	G12	J18	800
I/O	2	-	F16	J22	803
I/O	2	-	-	J19	806
I/O	2	P141	G13	H19	812
I/O (D2)	2	P142	F15	H20	815
V _{CCINT}	-	P143	V _{CCINT} *	V _{CCINT} *	-
V _{CCO}	2	P144	V _{CCO} Bank 2*	V _{CCO} Bank 2*	-
GND	-	P145	GND*	GND*	-
I/O (D1)	2	P146	E16	H22	818
I/O, V _{REF}	2	P147	F14	H18	821
I/O	2	-	-	G21	824
I/O	2	P148	D16	G18	827
I/O	2	-	F12	G20	830
I/O	2	-	-	G19	833
I/O	2	-	-	F22	836
I/O	2	P149	E15	F19	839
I/O, V _{REF}	2	P150	F13	F21	842
V _{CCO}	2	-	V _{CCO} Bank 2*	V _{CCO} Bank 2*	-
GND	-	-	GND*	GND*	-
I/O	2	P151	E14	F20	845
I/O	2	-	C16	F18	848
I/O	2	-	-	E22	851
I/O	2	-	-	E21	854
I/O	2	P152	E13	D22	857
GND	-	-	GND*	GND*	-
I/O	2	-	B16	E20	860
I/O	2	-	-	D21	863

XC2S150 Device Pinouts (Continued)

XC2S150 Pad Name		PQ208	FG256	FG456	Bndry Scan
Function	Bank				
I/O	2	-	-	C22	866
I/O (DIN, D0)	2	P153	D14	D20	869
I/O (DOUT, BUSY)	2	P154	C15	C21	872
CCLK	2	P155	D15	B22	875
V _{CCO}	2	P156	V _{CCO} Bank 2*	V _{CCO} Bank 2*	-
V _{CCO}	1	P156	V _{CCO} Bank 1*	V _{CCO} Bank 1*	-
TDO	2	P157	B14	A21	-
GND	-	P158	GND*	GND*	-
TDI	-	P159	A15	B20	-
I/O ($\overline{\text{CS}}$)	1	P160	B13	C19	0
I/O ($\overline{\text{WRITE}}$)	1	P161	C13	A20	3
I/O	1	-	-	B19	6
I/O	1	-	-	C18	9
I/O	1	-	C12	D17	12
GND	-	-	GND*	GND*	-
I/O	1	P162	A14	A19	15
I/O	1	-	-	B18	18
I/O	1	-	-	E16	21
I/O	1	-	D12	C17	24
I/O	1	P163	B12	D16	27
GND	-	-	GND*	GND*	-
V _{CCO}	1	-	V _{CCO} Bank 1*	V _{CCO} Bank 1*	-
I/O, V _{REF}	1	P164	C11	A18	30
I/O	1	P165	A13	B17	33
I/O	1	-	-	E15	36
I/O	1	-	-	A17	39
I/O	1	-	D11	D15	42
I/O	1	P166	A12	C16	45
I/O	1	-	-	D14	48
I/O, V _{REF}	1	P167	E11	E14	51
I/O	1	P168	B11	A16	54
GND	-	P169	GND*	GND*	-
V _{CCO}	1	P170	V _{CCO} Bank 1*	V _{CCO} Bank 1*	-
V _{CCINT}	-	P171	V _{CCINT} *	V _{CCINT} *	-
I/O	1	P172	A11	C15	57
I/O	1	P173	C10	B15	60
I/O	1	-	-	A15	66
I/O	1	-	-	F12	69

XC2S200 Device Pinouts (Continued)

XC2S200 Pad Name		PQ208	FG256	FG456	Bndry Scan
Function	Bank				
V _{CCO}	3	P117	V _{CCO} Bank 3*	V _{CCO} Bank 3*	-
V _{CCINT}	-	P118	V _{CCINT} *	V _{CCINT} *	-
I/O (D5)	3	P119	M16	R21	833
I/O	3	P120	K14	P18	836
I/O	3	-	-	R22	839
I/O	3	-	-	P19	842
I/O	3	-	L16	P20	845
GND	-	-	GND*	GND*	-
I/O	3	P121	K13	P21	848
I/O	3	-	-	N19	851
I/O	3	-	-	P22	854
I/O	3	P122	L15	N18	857
I/O	3	P123	K12	N20	860
GND	-	P124	GND*	GND*	-
V _{CCO}	3	-	V _{CCO} Bank 3*	V _{CCO} Bank 3*	-
I/O, V _{REF}	3	P125	K16	N21	863
I/O (D4)	3	P126	J16	N22	866
I/O	3	-	-	M17	872
I/O	3	-	J14	M19	875
I/O	3	P127	K15	M20	878
I/O	3	-	-	M18	881
V _{CCINT}	-	P128	V _{CCINT} *	V _{CCINT} *	-
I/O, TRDY ⁽¹⁾	3	P129	J15	M22	890
V _{CCO}	3	P130	V _{CCO} Bank 3*	V _{CCO} Bank 3*	-
V _{CCO}	2	P130	V _{CCO} Bank 2*	V _{CCO} Bank 2*	-
GND	-	P131	GND*	GND*	-
I/O, IRDY ⁽¹⁾	2	P132	H16	L20	893
I/O	2	P133	H14	L17	896
I/O	2	-	-	L18	902
I/O	2	P134	H15	L21	905
I/O	2	-	J13	L22	908
I/O	2	-	-	K19	911
I/O (D3)	2	P135	G16	K20	917
I/O, V _{REF}	2	P136	H13	K21	920
V _{CCO}	2	-	V _{CCO} Bank 2*	V _{CCO} Bank 2*	-
GND	-	P137	GND*	GND*	-
I/O	2	P138	G14	K22	923
I/O	2	P139	G15	J21	926

XC2S200 Device Pinouts (Continued)

XC2S200 Pad Name		PQ208	FG256	FG456	Bndry Scan
Function	Bank				
I/O	2	-	-	K18	929
I/O	2	-	-	J20	932
I/O	2	P140	G12	J18	935
GND	-	-	GND*	GND*	-
I/O	2	-	F16	J22	938
I/O	2	-	-	J19	941
I/O	2	-	-	H21	944
I/O	2	P141	G13	H19	947
I/O (D2)	2	P142	F15	H20	950
V _{CCINT}	-	P143	V _{CCINT} *	V _{CCINT} *	-
V _{CCO}	2	P144	V _{CCO} Bank 2*	V _{CCO} Bank 2*	-
GND	-	P145	GND*	GND*	-
I/O (D1)	2	P146	E16	H22	953
I/O, V _{REF}	2	P147	F14	H18	956
I/O	2	-	-	G21	962
I/O	2	P148	D16	G18	965
GND	-	-	GND*	GND*	-
I/O	2	-	F12	G20	968
I/O	2	-	-	G19	971
I/O	2	-	-	F22	974
I/O	2	P149	E15	F19	977
I/O, V _{REF}	2	P150	F13	F21	980
V _{CCO}	2	-	V _{CCO} Bank 2*	V _{CCO} Bank 2*	-
GND	-	-	GND*	GND*	-
I/O	2	P151	E14	F20	983
I/O	2	-	C16	F18	986
GND	-	-	GND*	GND*	-
I/O	2	-	-	E22	989
I/O	2	-	-	E21	995
I/O, V _{REF}	2	P152	E13	D22	998
GND	-	-	GND*	GND*	-
I/O	2	-	B16	E20	1001
I/O	2	-	-	D21	1004
I/O	2	-	-	C22	1007
I/O (DIN, D0)	2	P153	D14	D20	1013
I/O (DOUT, BUSY)	2	P154	C15	C21	1016
CCLK	2	P155	D15	B22	1019
V _{CCO}	2	P156	V _{CCO} Bank 2*	V _{CCO} Bank 2*	-